# Microwave dielectric properties of B<sub>2</sub>O<sub>3</sub> doped LaAlO<sub>3</sub> ceramics at low sintering temperature

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The microwave dielectric properties and the microstructures of LaAlO<sub>3</sub> ceramics with B<sub>2</sub>O<sub>3</sub> additions (0.25–1 wt%) prepared with conventional solid-state route have been investigated. Doping with B<sub>2</sub>O<sub>3</sub> (up to 0.5 wt%) can effectively promote the densification of LaAlO<sub>3</sub> ceramics. It is found that LaAlO<sub>3</sub> ceramics can be sintered at 1400°C due to the liquid phase effect of B<sub>2</sub>O<sub>3</sub> addition. The  $Q \times f$  value as well as the dielectric constant decreases at higher B<sub>2</sub>O<sub>3</sub> doping level (1 wt%) due to the increase of boundary phases. At 1460°C, LaAlO<sub>3</sub> ceramics with 0.5 wt% B<sub>2</sub>O<sub>3</sub> addition possesses a dielectric constant ( $\varepsilon_r$ ) of 22.9, a  $Q \times f$  value of 44700 (at 9 GHz) and a temperature coefficients of resonant frequency ( $\tau_f$ ) of -36 ppm/°C. The B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics can find applications in microwave devices requiring low sintering temperature. © *2003 Kluwer Academic Publishers* 

## 1. Introduction

Recently, many researchers have been focusing on developing dielectric materials with high quality factor  $(Q \times f)$ , high dielectric constant  $(\varepsilon_r)$  and zero temperature coefficient of resonant frequency  $(\tau_f)$  for the use of dielectric resonator and microwave device substrate. High dielectric constant material can effectively reduce the size of resonators since that the wavelength ( $\lambda$ ) in dielectrics is inversely proportional to  $\sqrt{\varepsilon_r}$  of the wavelength  $(\lambda_o)$  in vacuum  $(\lambda = \lambda_o / \sqrt{\varepsilon_r})$ . The inverse of the dielectric loss ( $Q = 1/\tan \delta$ ) is required to be high for achieving prominent frequency selectivity and stability in microwave transmitter components and small temperature coefficient of the resonant frequency is to ensure the stability of the microwave components at different working temperature. Several compounds such as (Zr, Sn)TiO<sub>4</sub>, Ba(Mg<sub>1/3</sub>Ta<sub>1/3</sub>)O<sub>3</sub> and  $(Mg, Ca)TiO_3$  have therefore been developed [1–3]. Rare-earth aluminates LaAlO<sub>3</sub>, has been widely used as substrate for superconducting microwave devices since it provides a high quality factor, excellent lattice matching and a good matching for thermal expansion. A phase transition of LaAlO<sub>3</sub> occurs at ~800 K from the high temperature cubic phase (space group Pm3m) to the rhombohedral phase (space group R3c) [4]. It possesses suitable microwave dielectric properties ( $\varepsilon_r \sim 23$ ,  $Q \times f \sim 65000$  GHz,  $\tau_f \sim -44$  ppm/°C) [5] for applications in dielectric resonators. However, it also requires high sintering temperatures (1550-1650°C). The crystal structure of LaAlO<sub>3</sub> exhibits rhombohedral symmetry.

Chemical processing and small particle sizes of the starting materials are generally advantageous to reduce the sintering temperature of dielectric materials [6–8]. However, they required a flexible procedure not only

expansive but time consuming in the fabrication of dielectric resonator. In this paper,  $B_2O_3$  was selected as a sintering aid in LaAlO<sub>3</sub> material since the liquid phase sintering by adding glass or other low melting point material can effectively lower the sintering temperature of ceramics [7]. Moreover, the microwave dielectric properties of dielectric resonators could be affected due to the development of a particular microstructure linked to the reaction between host material and addition or the sintering with a liquid phase. The crystalline phases, the microstructures and the microwave dielectric properties of  $B_2O_3$ -doped LaAlO<sub>3</sub> ceramics were investigated.

## 2. Experimental

Samples of LaAlO<sub>3</sub> were synthesized by conventional solid state method. The starting materials were mixed according to a stoichiometric ratio. A small amount of  $B_2O_3$  (0.25–1 wt%) was added as a sintering aid. High purity oxide powders (>99.9%) La<sub>2</sub>O<sub>3</sub>, Al<sub>2</sub>O<sub>3</sub> and B<sub>2</sub>O<sub>3</sub> were weighted and mixed for 24 h with distilled water. The mixture was dried at 100°C and thoroughly milled before it was calcined at 1100°C for 2 h. The calcined powder was ground and sieved through 100-mesh screen. Phase formation of LaAlO<sub>3</sub> was confirmed using X-ray diffraction. The fine powder together with the organic binder was pressed into pellets with dimensions of 11 mm in diameter and 5 mm in thickness. These pellets were sintered at temperatures of 1340–1460°C for 2 h in air. The heating rate and the cooling rate were both set at 10°C/min.

The powder and bulk X-ray diffraction (XRD, Rigaku D/Max III. V) spectra were collected using Cu K $\alpha$  radiation (at 30 Kv and 20 mA) and a graphite monochromator in the  $2\theta$  range of  $20^{\circ}$  to  $60^{\circ}$ . The

microstructural observations and the analysis of sintered surface were performed by a scanning electron microscopy (SEM, Philips XL-40FEG).

The bulk relative densities of the sintered pellets were measured by the Archimedes method. The dielectric constant ( $\varepsilon_r$ ) and the quality factor values (Q) at microwave frequencies were measured using the Hakki-Coleman [9] dielectric resonator method as modified and improved by Courtney [10]. The dielectric resonator was positioned between two brass plates. A system combined with a HP8757D network analyzer and a HP8350B sweep oscillator was employed in the measurement. Identical technique was applied in measuring the temperature coefficient of resonant frequency ( $\tau_f$ ). The test set was placed over a thermostat in the temperature range from +25°C to +80°C. The  $\tau_f$  value (ppm/°C) can be calculated by noting the change in resonant frequency ( $\Delta f$ ),

$$\tau f = \frac{f_2 - f_1}{f_1 (T_2 - T_1)} \tag{1}$$

where  $f_1$  and  $f_2$  represent the resonant frequencies at  $T_1$  and  $T_2$ , respectively.

#### 3. Results and discussion

Fig. 1 shows the X-ray diffraction patterns of 0.25 wt%B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics at different sintering temperatures (1340–1460°C). All of the XRD profiles of the ceramics samples can be indexed by pseudocubic unit cell of the perovskite structure. The X-ray diffraction patterns of the LaAlO<sub>3</sub> ceramics have not significant change with 0.25 wt% B<sub>2</sub>O<sub>3</sub> addition at sintering temperatures 1340–1460°C. Second phase was not observed by XRD at the level of 0.25 wt% B<sub>2</sub>O<sub>3</sub> addition.

The X-ray diffraction patterns of LaAlO<sub>3</sub> ceramics with different amounts of  $B_2O_3$  additions sintered at 1460°C are illustrated in Fig. 2. Identical XRD patterns were observed for the ceramics regardless the amount of  $B_2O_3$  additions.

The SEM photographs of  $B_2O_3$ -doped LaAlO<sub>3</sub> at sintering temperatures of 1340–1460°C are shown in



*Figure 1* X-ray diffraction patterns of 0.25 wt% B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics at different sintering temperatures.



*Figure 2* X-ray diffraction patterns of LaAlO<sub>3</sub> ceramics with different amount of  $B_2O_3$  addition sintered at 1460°C.

Fig. 3. The grain size increased with the increase of sintering temperature as well as amount of  $B_2O_3$  addition due to the liquid phase effect. With 0.25–0.5 wt%  $B_2O_3$  additions, porous specimens were observed for LaAlO<sub>3</sub> ceramics sintered at temperatures 1340–1400°C. Dense samples can be obtained at sintering temperatures above 1430°C. However, the grain boundary phases were pronounced product with 1 wt%  $B_2O_3$  addition. It may directly affect the microwave dielectric properties of the ceramic samples.

The relative density of the B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics at different sintering temperatures is shown in Fig. 4. It indicated that relative densities of 91.4%–99% were obtained for B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics at sintering temperatures from  $1340^{\circ}$ C to  $1460^{\circ}$ C. The relative density increased with increasing sintering temperature due to enlarged grain size as observed in Fig. 3, and was also affected by the B<sub>2</sub>O<sub>3</sub> addition. Higher B<sub>2</sub>O<sub>3</sub> doping level formed more liquid phase, which would enhance the densification resulted in a higher ceramic relative density. Moreover, the relative density also related to the porosity and increased with the decrease of porosity. As the sintering temperature increased, the relative density slightly increased and reached 98% at  $1460^{\circ}$ C with 0.5 wt% B<sub>2</sub>O<sub>3</sub> addition.

Fig. 5 demonstrates the dielectric constants of LaAlO<sub>3</sub> ceramics with different amount of B<sub>2</sub>O<sub>3</sub> additions as functions of their sintering temperatures. The relationships between  $\varepsilon_r$  values and sintering temperatures revealed the same trend with those between relative densities and sintering temperatures since higher relative density means lower porosity. The dielectric constants slightly increased with increasing sintering temperature. The increase in the  $\varepsilon_r$  value could be explained owing to higher relative densities. However, a dramatic degradation in the  $\varepsilon_r$  value appeared at 1 wt% B<sub>2</sub>O<sub>3</sub> doping level. It was attributed to the low dielectric constant of the liquid phase. With 0.5 wt% B<sub>2</sub>O<sub>3</sub> addition, an  $\varepsilon_r$  value of 22.9 was obtained for LaAlO<sub>3</sub> ceramics sintered at 1460°C.

Fig. 6 shows the  $Q \times f$  values of LaAlO<sub>3</sub> ceramics with various B<sub>2</sub>O<sub>3</sub> additions at different sintering temperatures. At low level of B<sub>2</sub>O<sub>3</sub> additions (0.25–1 wt%), the  $Q \times f$  values of LaAlO<sub>3</sub> ceramics increased with increasing sintering temperature.

However, higher  $Q \times f$  values were observed at 0.5 wt% B<sub>2</sub>O<sub>3</sub> doping level. With increasing B<sub>2</sub>O<sub>3</sub> content, the  $Q \times f$  value increased to a maximum value of 44700 (GHz) at 0.5 wt% and thereafter decreased. The microwave dielectric loss is mainly caused

not only by the lattice vibrational modes, but also by the pores and the secondary phases. Smaller grain size as well as higher porosity degraded the  $Q \times f$ values of the as-sintered samples with 0.25 wt% B<sub>2</sub>O<sub>3</sub> addition. Relative density also plays an important role





1340°C

1430°C



1370°C



1460°C



Figure 3 SEM photographs of LaAlO<sub>3</sub> ceramics with (a) 0.25 wt% (b) 0.5 wt% and (c) 1 wt%  $B_2O_3$  additions at different sintering temperatures. (Continued)

(a)



1340°C



1430°C



1370°C



1460°C



1400°C

(b)

Figure 3 (Continued).

in controlling the dielectric loss and has been shown for other microwave dielectric materials. With  $0.5 \ wt\%$  $B_2O_3$  addition, the  $Q \times f$  value increased from 21000 to 44700 (GHz) as the sintering temperature increased from 1340 to 1460°C for 2 h. It was consistent with the

variation of relative density. Furthermore, higher B2O3 content would degrade the  $Q \times f$  value of LaAlO<sub>3</sub> ceramics since the grain boundary phases were pronounced product at higher sintering temperatures as observed in Fig. 3. That would explain the decrease in



1340°C



1430°C



1370°C



1460°C



1400°C

(c)

Figure 3 (Continued).

 $Q \times f$  values for LaAlO<sub>3</sub> ceramics with 1 wt% B<sub>2</sub>O<sub>3</sub> addition. The quality factors of B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics were relatively lower than that of pure LaAlO<sub>3</sub> ceramics due to the grain boundary phase.

The temperature coefficients of resonant frequency  $(\tau_f)$  of B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics at different sin-

tering temperatures are illustrated in Fig. 7. The temperature coefficient of resonant frequency is well known related to the composition, the additives and the second phase of the material. The  $\tau_f$  value, as presented, was a function of the B<sub>2</sub>O<sub>3</sub> content. It varied from average -26 to -35 ppm/°C as the amount of B<sub>2</sub>O<sub>3</sub>



*Figure 4* Dependence of sintering temperature of  $LaAlO_3$  ceramics on relative density with various  $B_2O_3$  additions.



Figure 5 Dependence of sintering temperature of LaAlO<sub>3</sub> ceramics on dielectric constant with various  $B_2O_3$  additions.



*Figure 6* Dependence of sintering temperature of LaAlO<sub>3</sub> ceramics on quality factor ( $Q \times f$ ) with various B<sub>2</sub>O<sub>3</sub> additions.

addition increased from 0.25 to 0.5–1 wt%. Significant change was not observed in the  $\tau_f$  value with fixed B<sub>2</sub>O<sub>3</sub> addition at different sintering temperatures. It implies that the  $\tau_f$  value was not sensitive to the sintering temperature.



*Figure 7* Dependence of sintering temperature of LaAlO<sub>3</sub> ceramics on  $\tau_f$  value with various B<sub>2</sub>O<sub>3</sub> Additions.

### 4. Conclusion

The dielectric properties of B<sub>2</sub>O<sub>3</sub>-doped LaAlO<sub>3</sub> ceramics were investigated. LaAlO<sub>3</sub> ceramics exhibited perovskite structure with pseudo-cubic unit cell. A tremendous sintering temperature reduction (100–200°C) can be achieved by adding B<sub>2</sub>O<sub>3</sub> to the LaAlO<sub>3</sub> ceramics. With 0.5 wt% B<sub>2</sub>O<sub>3</sub> addition, a dielectric constant of 22.9, a  $Q \times f$  value of 44700 (GHz) and a  $\tau_f$  value of -36 ppm/°C were obtained for LaAlO<sub>3</sub> ceramics at 1460°C for 2 h. The decrease in  $Q \times f$  value at higher B<sub>2</sub>O<sub>3</sub> addition (1 wt%) was owing to that the grain boundary phases were pronounced product.

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#### References

- 1. S. NOMURA, K. TOYAMA and K. KANETA, *Jpn. J. Appl. Phys.* **21** (1982) L624.
- 2. G. WOLFRAM and H. E. GOBEL, *Mater. Res. Bull.* **16** (1981) 1455.
- 3. I. BURN, U.S. patent 4,845,062 (1989).
- 4. PAI-HSUAN SUN, TETSURO NAKAMURA, YUE JIN SHAN, YOSHIYUKI INAGUMA and MITSURU ITOH, *Jpn. J. Appl. Phys.* **37** (1998) 5625.
- 5. SEO-YONG CHO, IN-TAE KIM and KUG-SUN HONG, J. Mater. Res. 14 (1999) 114.
- T. KAKADA, S. F. WANG, SYOSHIKAWA, S. T. JANG and R. E. NEWNHAM, J. Amer. Ceram. Soc. 77 (1994) 1909.
- 7. S. I. HIRNO, TAKASHI, HAYASHI and A. HATTORI, *ibid.* **74** (1991) 1320.
- 8. V. TOLMER and G. DESQUARDIN, *ibid.* 80 (1997) 1981.
- 9. B. W. HAKKI and P. D. COLEMAN, *IEEE Trans. Microwave Theory & Tech.* 8 (1960) 402.
- 10. W. E. COURTNEY, *ibid.* 18 (1970) 476.

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